

Amendments to the Claims

Claims 1-5 (*Cancelled*)

6. (*Previously Presented*) An MIS type semiconductor device, comprising:

- a semiconductor substrate,
- a gate electrode formed on the gate insulating film and formed of gate material, wherein the gate electrode comprises:
 - a first layer of activated crystalline gate material having a first side oriented towards a substrate and a second side oriented away from the substrate, the first layer of activated crystalline gate material having a doping level of 10^{19} ions/cm³ or higher, and
 - a second layer of gate material at the second side of the first layer of activated crystalline gate material.

7. (*Previously Presented*) A semiconductor device according to claim 6, wherein the first layer of activated crystalline gate material has a doping level of about 10^{20} ions/cm³ or higher.

8. (*Previously Presented*) An MIS type semiconductor device according to claim 6, wherein the doping implant in the activated gate material has an abruptness of about 2 nm or more.

9. (*Previously Presented*) A semiconductor device according to claim 6, wherein the second layer of gate material consists of amorphous gate material.

10. (*Previously Presented*) A semiconductor device according to claim 6, wherein the second layer of gate material consists of polycrystalline gate material.

11. (*Previously Presented*) A semiconductor device according to claim 6, wherein the grain size in the second layer is below about 40 nm.

12. *(Original)* A semiconductor device according to claim 6, wherein the first layer is crystalline or very fine-grained, with grains below 5 nm.

13. *(Previously Presented)* A semiconductor device according to claim 6, wherein a gate insulator is provided between the semiconductor substrate and the gate electrode.

14. *(Original)* A semiconductor device according to claim 6, wherein the device is a transistor.

15. *(Cancelled)*

16. *(Cancelled)*

17. *(Previously Presented)* A semiconductor device according to claim 6, wherein the first layer of activated crystalline gate material has a doping level of about 5×10^{20} ions/cm³ or higher.

18. *(Previously Presented)* An MIS type semiconductor device according to claim 6, wherein the doping implant in the activated gate material has an abruptness of about 1.5 nm or more.

19. *(Previously Presented)* An MIS type semiconductor device according to claim 6, wherein the doping implant in the activated gate material has an abruptness of about 1 nm.

20. *(Previously Presented)* A semiconductor device according to claim 6, wherein the grain size in the second layer is below about 30 nm.